SPring-8 INDUSTRIAL APPLICATIONS

Outline

- 1. Why did we start promoting industrial use?
- 2. Industrial support organization
- 3. Program for the industry supported by MEXT
 - a. Trial Use Program
 - b. Strategic Program for Utilization of Advanced Large-Scale Research Facilities
- 4. Public Beamlines for industrial applications
- 5. Highlights of industrial research works
- 6. User satisfaction
- 7. Summary

Norimasa Umesaki Industrials Application Division, JASRI/SPring-8



The annual trend of the Number and Percentage of Industrial Research Proposals from the Companies.



Support Organization for Industrial Use

- Since fiscal 2001, <u>the Industrial Application/Utilization Support Group</u> started with three coordinators, eight technical staff and three in the secretariat.
- In April 2003, <u>the Industrial Application/Utilization Support Group</u> was reorganized in order to enhance support for the industrial users with four coordinators, seven technical staff and two in the secretariat.
- In April 2005, in order to cope promptly with various forms of utilization by industrial application users and reinforcement of support for beamline utilization in future, the group became a division called *the Industrial Application Division*, and has been keeping its dynamic activities so far.



Staff of Industry Application Division

The industry application division was organized at JASRI/SPring-8 in April 2001.

≻Hard Materials Science:

4 coordinators

≻Soft Matter Science:

4 coordinators

Dr. Y. Watanabe (Semiconductor materials)
Dr. S. Komiya (Electronics devise)
Dr. N. Umesaki (Metal, inorganic, etc.)
Dr. T. Hashimoto (Structural steel)

Dr. M. Sugiura (Catalysis science)Dr. T. Ninomiya (Chemical analysis)Dr. Y. Ohashi (Crystallography)Dr. K. Horie (Polymer materials)

6 beamline scientists and **10** engineers

Secretariat (3 people)

SPring-8

Services Provided by Industry Application Division

 Promotion of industrial use
 Interface between companies and SPring-8
 Consultation on industrial subjects
 Training meetings and courses
 Technical and scientific support
 Management of public beamlines BL14B2, BL19B2 and BL46XU
 Industrial applications
 Collaboration with companies

Workshops and research meetings



Promoting Programs for Industrial Use

To increase the number of industrial users and application fields

Phase I (2001, 2003-2005)	Phase II (2005-present)
Trial Use Program	Strategic Program for Utilization of Advanced Large-scale Research Facilities
Adopted proposals: 40 proposals/year	Adopted proposals: 125 proposals/year
Adoption Priority: new industrial users	Adoption Priority: new industrial users
Proposal according to several analytical methods	Proposal according to industrial application fields
Support: 3 coordinators, 6 beamline staff	Support: 8 coordinators, 16 beamline staff

(Financial support of MEXT)



Annual Trend of Number of People and Companies using SPring-8

Number of people







The Annual Trend of the Number and Percentage of Industrial Research Proposals from the Companies







Utilization of SR of SPring-8

Feature

Advantage





- **Diffraction / Scattering X-rays:** the atom arrangement of the material and electronic density distribution or the time fluctuation of the atom
- Transmitted / Refracted X-rays: Microstructure observation of micron size and submicron size of materials and biological substance
- **Spectroscopic Analysis:** Electronic structure and ultra-trace element analysis

SPring. 8 Research Methods Used in the SR Science

X-ray Diffraction and Scattering

- Macromolecular crystallography
 X-ray diffraction under extreme conditions
 X-ray powder diffraction
- > Surface diffraction
- >Small angle scattering
- >Medium angle scattering
- **X**-ray magnetic scattering
- >X-ray diffuse scattering
- Residual stress analysis
- >Nuclear resonant scattering/Nuclear excitation
- >X-ray Optics

X-ray Imaging

- > Refraction-contrast imaging
- >Phase-contrast imaging
- >X-ray microtomography
- >X-ray fluorescence microscopy
- >X-ray microscopy
- >X-ray topography
- >X-ray holography
- >Photoelectron emission microscopy (PEEM)

Spectroscopy and Spectrochemical Analysis

- Photoelectron spectroscopy
 Atomic and molecular spectroscopy
 Compton scattering/Compton magnetic scattering
 X-ray inelastic scattering
 X-ray fluorescence spectroscopy
 XAFS (X-ray absorption fine structure)/X-ray absorption spectroscopy
 X-ray magnetic circular dichroism
 X-ray photon correlation spectroscopy
- >Infrared spectroscopy

High performance analysis tool

Radiation Effect

Material processingRadiation biology





Engineering Science Research Beamline (BL19B2)

SPring



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When X-rays penetrate in the substance, we can observe X-ray absorption and refraction images through substrate.



Incident X-rays
Transmitted X-rays
Refracted X-rays



Observation of contact behavior between glass-fibers in rubber and ice by refractioncontrast image

Example 2





DUNLOP SUMITOMO RUBBER INDUSTRIES, LTD.

SPri



SEM image of implanted glass fiber (33 μ m diameter)

Glass fibers implanted in tires for frozen road

The behavior of glass fibers on ice was unknown.



Experiments (3rd Station of BL19B2)



Compression and shearing machine







Shapes of glass fibers were clearly observed.

Real-time imaging of rubber and ice contact





Fibers don't transform, nor break.

Real-time imaging of rubber and ice contact



A result of observation



SPring

Direct observation of fiber glass behavior on ice is proving the engineering simulations for the development of a high-performance tire. Observation of contact behavior between glass-fibers in rubber and ice by refraction-contrast image

SPring

Summary

- Glass fibers drill into ice.
- Almost glass fibers were removed from the ice without breaking.

Observed images were used in a promotion video to advertise tires



Fig. 2. Three scenes of an in situ image monitored by X-ray radiography when a compression test is done on foam aluminum. (a) Foam aluminium begins to collapse at top and bottom. (b)Foam aluminium is collapsing. The center keeps its shape. (c) All the foams seem to be almost destroyed.

<2秒

When X-rays irradiate to the substance, we can observe florescent X-ray emission, photo electron emission and absorption form surface and bulk of the material.





X-ray Absorption Fine Structure (XAFS)

X-ray Photoelectron Spectroscopy (XPS)



μm Element Analysis X-ray Fluorescence Analysis

SPring-8 affects to Archeology

AD220~280: Three Countries struggles for supremacy in China. They have a literature saying a set of 100 mirror were given to messenger from Japan. In Japan, long argument continues where is the origin of Japan. There exist two candidates. The oldest literature in Japan is written in AD712



中国古代青銅鏡年表



戦国時代(Warring State period):BC5c~BC221 秦時代 (Qin Dynasty period):BC221~BC206 前漢時代(First term of Western Han period):BC206~BC7 新時代:BC7~AD25 後漢時代(Later term of Western Han period):AD25~AD221 三国・西晋時代 (Three Kingdoms / Western Jin period):AD221~AD317



Mirror with triangle edge and Gods & Beats design

Museum of Sumitomo, JASRI, Sumitomo Metals







 1. 三角縁三神五獣鏡(M23)
 2. 三角縁三神五獣鏡(M24)
 3. 三角縁四神四獣鏡(M25)
 4. 三角縁四神四獣鏡(M112)

 All 8 mirrors come from Japanese ancient tomb.



5. 三角縁二神二獣鏡(M116) 6. 三角縁三神三獣鏡(M33) 7. 三角縁三神二獣鏡(M118) 8. 三角縁三神三獣鏡(M119)

BL19B2 (SPring-8) エネルギー分散型蛍光X線スペクトロメーター



表面状態の違いによる数値の変動状況 三角縁三神五獣鏡(M24)鏡面上で、表面状況の異なる84点を測定する。







厚い錆に覆われている部分



薄い錆に覆われている部分



ほぼ地金と考えられる部分



Distribution of Impurities in Bronze Mirror by Fluorescence at Spring-8

When X-rays irradiate to the substance, we can observe Xray diffraction and scattering form surface and bulk of the materials.



X-ray Imaging

X-ray Fluorescence Analysis

X-ray Reflectometry

X-ray
 Diffraction/Scattering

X-ray Absorption Fine Structure (XAFS)

X-ray Photoelectron Spectroscopy (XPS)
~Å Structural Analysis at atomic Level X-ray Diffraction/Scattering



Highlights of Industrial Researches carried out at BL19B2

• Example 1

In-situ Observations of Formation of Fe-Zn Intermetallic Compounds during Galvannealing Process by XRD

• Example 2

Grazing Incidence X-ray Diffraction of Amorphous SiO_x Thin Film

• Example 3

In Situ Observation for Weld Solidification Process of Carbon Steel Metals

In-situ Observation of Alloying of Galvanized Steel

Example 1



Fe[`]-Zn 母材 ø34152 10.0kv x3.00k^{··}10.10[·]

- Property of galvanized steel is strongly depends on kind of Fe-Zn intermetallic compounds (FeZn₁₀: σ_1 phase and FeZn₁₃: ζ phase) at interface.
- \bullet δ₁(FeZn₁₀) phase is preferable.



Fe (base)



Process of galvanization





How (When) δ_1 phase forms in annealing process? In-situ observation of forming alloys during annealing process

Experiments (2nd Station of BL19B2)



In-situ observation of alloying of galvanized steel

1. Sample

Zn-0.14mass%AI galvanized steel, and pure Zn galvanized steel

<u>2. Annealing (alloying)</u>

IR Lamp annealing from backside of sheet



Variation of diffraction profiles to annealing time



A. Taniyama, M.Arai, T. Takayama, M. Sato, Material Transaction Vol.45, No. 7 (2004) p.2326

Dependences of diffraction intensities on annealing time



- A) <u>Zn-0.14mass%Al galvanized steel</u>: Alloying of Al containing galvanized steel was completed in 70 seconds at 753K.

 Suggesting layer-by-layer forming of alloy
- B) <u>Pure Zn galvanized steel</u>: The of ζ phase in galvanized with pure Zn decreased after 70 sec.



Dependences of diffraction intensities on annealing time





Assuming that the δ_1 phase grows in a layer-by-layer manner, the time dependence of thickness was estimated as shown in this equation.

The estimated thickness of the δ_1 phase increased by the parabolic law with annealing time, taking into account the incubation period (t_{inc}).

These results suggest that the growth of δ_1 phase is dominated by a diffusion of Fe atoms and Zn atoms in the coating.





A. Taniyama, M. Arai, T. Takayama and M. Sato: "In-Suit Observation of Growth Behavior of Fe-Zn Intermetallic Compounds at Initial Stage of Galvaannealing Process", Mat. Trans., 47(2004) 2326.



(lower than critical angle)

High sensitivity to the films on substrate



Preparation of SiO_x Film

• SiO_x film deposited on Si wafer

ECR plasma sputtering with flowing O₂ gas 1 sccm

These films are used for anti-reflection coating film



• Reference : bulk silicate glass plate

Characterization of the SiO_x film **Reflectivity of the SiO**_x film



Thickness	58.6 nm	
Roughness	0.5 nm	
Density	2.154 g/cm ³	
Observed at BL16B2 in SPring8		

Visible Ellipsometry (He-Ne laser)

Refractive index 2.6 absorption coefficient 0.13



Penetration depth is several nanometers under the critical angle

High surface sensitivity







Real Space Correlation Functions



Real space correlation functions for a monatomic amorphous solid.





HIGH ENERGY X-RAY STUDY ON THE STRUCTURE OF VITREOUS B₂O₃

K. Suzuya, S. Kohara, Y. Yoneda and N. Umesaki: Phys. Chem. Glasses, 41 (2000), 282.



FSDP:First Sharp Diffraction Peak



Observed X-ray diffraction profiles



Clear difference from bulk silica



Interference function



RDF of the deposited amorphous SiO_x film



The RDF of the SiOx film has the peaks at 0.235nm and 0.388nm. As for silicon crystal, the interatomic distances of the first and second nearest neighbors are 0.235nm and 0.384nm. However, there is no indication of the pair correlations of third and forth nearest neighbors in silicon crystal in the RDF of the film. This result suggests that the film is composed of tetrahedron formed by silicon. Thus it is considered that silicon atoms of the film are partially oxidized.

Tetrahedron of Si crystal

1st nearest	0.235nm
2nd nearest	0.385nm



The film is composed of Si tetrahedra (not Si-O tetrahedra)



Summary

- Studying SiO_x film deposited on Si substrate by ECR sputtering with grazing incidence X-ray scattering (GIXS).
- The radial distribution function derived from scattering profile revealed that the SiO_x film was composed of silicon tetrahedra.
- It is concluded that silicon atoms of the film are partially oxidized.
- GIXS is a valuable technique to study the structure of amorphous thin film.

In-situ observation for weld solidification process of carbon steel metal

SUMITOMO METAL INDUSTRIES,LTD.

Solidification Crack



Countermeasure

Narrowing the solidification temperature range where the ductility of the steel decreases:

Raising the solidification temperature

 \rightarrow Control of the phase evolution during the rapid cooling by the matrix composition of the steel

Guideline for the material design



In-situ observation of weld solidification process during the rapid cooling (~500K/sec)

Time resolved X-ray diffraction measurement by Silicon Pixel Detector **PILATUS**



INTERNAL INTERNAL

SPEC: pixel size 217 µ m 366 × 157 Number of pixel area of detector 79.4mm × 34.mm **Digital clock** 10MHz readout time 6.7msec

Upgraded version PILATUS II has been installed at 2006.

Layout of experiment

Upstream side view





BL46XU Multi-axis Diffractometer

Downstream side view



Time change of temperature with the torch motion



Variation of diffraction profiles during solidification II





Complicated phase evolution with solid transformation

It is impossible to investigate the solidification process by the exsitu observation of quenched solidification microstrucures.







A State Analysis

XAFS

<u>XAFS</u>

(X-ray Absorption Fine Structure)



XANES: electronic state (valence) EXAFS: local structure (coordination number, distance)

Principle schemes of XAFS measurements



Characterization of blue phosphor for PDP by XAFS

Study of fading of light emitting from BaMgAl₁₀O₁₇ during production of PDP panel



Cell structure of PDP





Visible light is emitted from UV irradiated phosphor.

Blue Phosphor : $Ba_{1-x}Eu_{x}MgAl_{10}O_{17}$ (BAM)

Electrode

What occurs in phosphor by UV irradiation? Effect of irradiation was investigated by XAFS

Experimental condition of XAFS of Eu-L₃

1st Station of BL19B2

SPring



<u>Samples</u>

Irradiated (BaEu)MgAl₁₀O₁₇ Non-irradiated (BaEu)MgAl₁₀O₁₇

References EuCl₂

EuCl₃



Change of the local structure of Eu in BaMgAl₁₀O₁₇ during heating by XAFS



Heating > Oxidization of Eu > Change of the local structure around Eu

(Appendix)

Mechanism of fading of light emitting from BaMgAl₁₀O₁₇:Eu during heating



Fading of light emitting during heating is caused by selective oxidation of Eu controlled by oxygen diffusion from atmosphere.

I. Hirosawa, J. SID . 12, 269 (2004)


Characterization of blue phosphor for PDP by XAFS

Summary

The fading of blue light is originated in oxidation of Eu in the phosphor.



Next step: Clarification of change of local structure around Eu by irradiation.

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Industrial User Evaluation of *"Trial Use Program"*



• The answer to the questionnaire by the industrial users :



• <u>Result of this program</u>:

> Many new industrial users joined the program.

• <u>Unresolved subject</u>:

> Beam time is not enough to create direct contribution for the development of actual products.

Industrial User Evaluation of "*Strategic Program for Utilization of Advanced Large-scale Research Facilities*"

Questions



Realization of barrier-free of the users' experiments by reinforcement of the support system

Answer rate of the questionnaire:75% (85 replied proporsa1s / 117 sent proposals)

Summary



- Industrial applications have been steadily increasing for these five years, as a result of the MEXT programs and the effort of our staff and users. Utilization of SPring-8 has become familiar to the industry, and there has been an active entry of new businesses and from new fields, resulting in a total of 2,200 users from 170 companies visiting SPring-8 to perform experiments in 2005.
- Expansion in utilization and accumulated results suggest various issues and direction for the future. The main issues are the promotion of utilization by non-specialists, and utilization that leads directly to business and the way to secure utilization opportunities for such purposes.
- It is now essential to reconstruct the beamlines, experimental equipment, utilization system and the organization comprehensively to accept various users and to produce good results.

Thank you for listening.

Special thanks to:

Staff of the Industrial Application Division Industrial Users

Small-angle X-ray diffraction using a microbeam at BL40XU (High Flux Beamline)

V-mirror

H-mirror

 \cdot Two pinholes

Storage Ring

helical

undulator

 CCD camera combined with an imaging intensifier

Mask &

FE-slits

Experiment Hair cuticle (Inoue *et al.* Kanebo Cosmetics Inc.)



(Appendix) Structural Analysis of Human Hair Cuticle using Micro-beam X-ray Diffraction

- Relationship with Effects of Hair Dyeing (T. Inoue et al.) -







Camera length : ~ 160m
Wide q-range : 10⁻⁴ ~ 10⁻¹ Å⁻¹
Exposure time : < 100 ms



In situ XAFS study on cathode materials for Li-ion batteries

SPring-8, BL16B2(The industrial consortium beam line)



The experimental setup for Ni K-edge XAFS measurements in a transmission mode.



Ni K-edge XANES spectra for $\text{LiNi}_{0.8}\text{Co}_{0.2}\text{O}_2$.

In situ XAFS study on cathode materials for Li-ion batteries



In situ XAFS study on cathode materials for Li-ion batteries





In situ XAFS study on cathode materials for Li-ion batteries

Initial state

Ni valence \cdots lower \rightarrow higher valence upon charging (NiO₆) octahedron \cdots distorted \rightarrow regular **Deteriorated state (Capacity fading)** Ni valence \cdots high valence (NiO₆) octahedron \cdots regular

Li ions can not come back to the cathode?

By using these in situ XAFS methods, they are now studying some modified cathode materials.